

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 2004-125715

(43)Date of publication of application : 22.04.2004

(51)Int.Cl.

G01N 23/04

(21)Application number : 2002-293146

(71)Applicant : YAMATO SCALE CO LTD

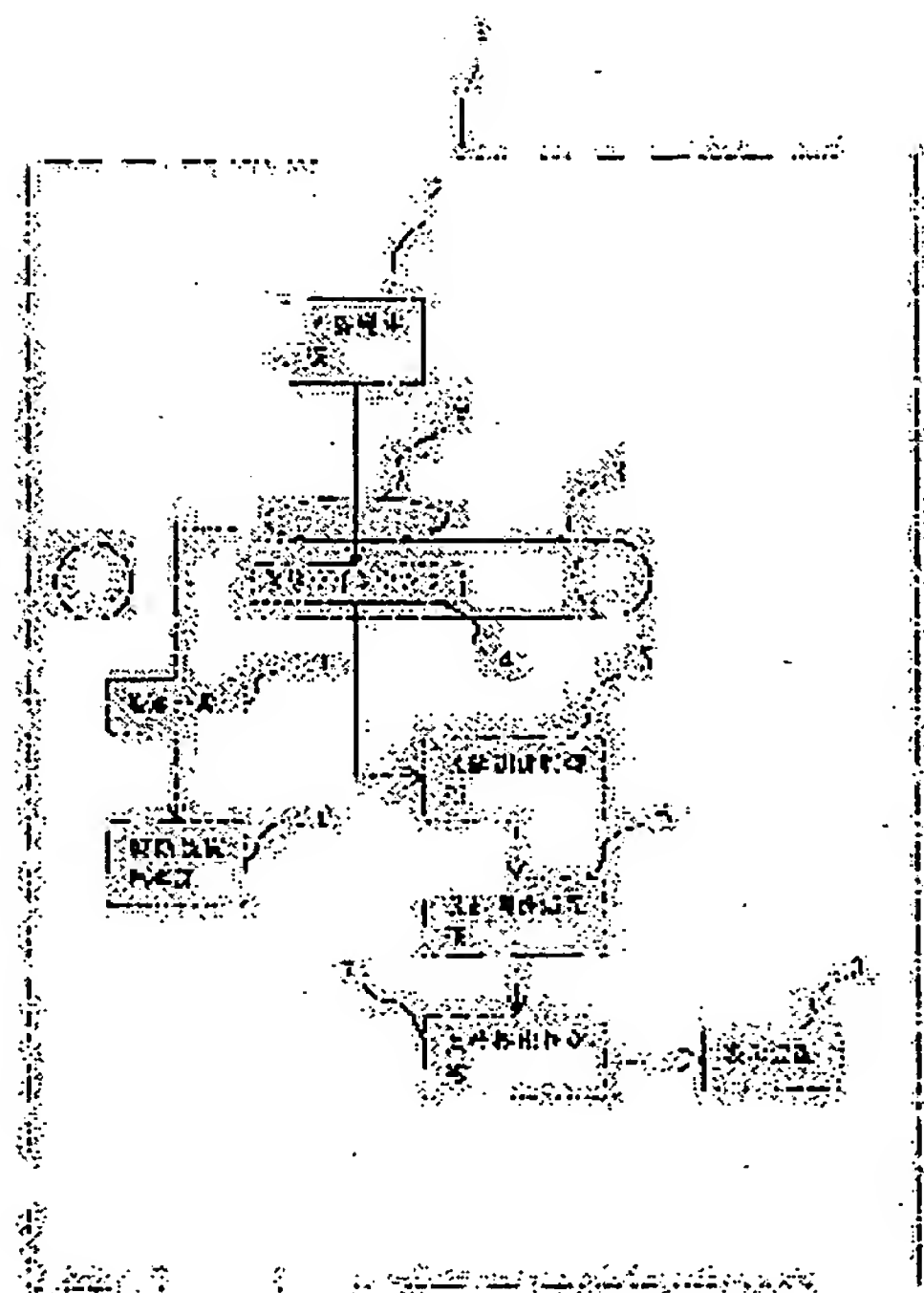
(22)Date of filing : 07.10.2002

(72)Inventor : KAWANISHI KATSUZO
OKITA KOICHI(54) METHOD AND APPARATUS FOR CALIBRATING SENSITIVITY OF X-RAY FOREIGN
MATTER INSPECTION INSTRUMENT

(57)Abstract:

PROBLEM TO BE SOLVED: To provide a method and apparatus for calibrating sensitivity capable of effectively calibrating sensitivity of an X-ray foreign matter inspection instrument using an foreign matter sample.

SOLUTION: An X-ray foreign matter inspection instrument detects a foreign matter included in a measured sample by transmitting an X-ray. The calibrating apparatus includes a moving means causing the foreign sample to pass a foreign matter detector of the inspection instrument, emits an X-ray to the foreign matter, and calibrates the inspection instrument sensitivity by using on a foreign matter detection signal output based on image data of the transmitted X-ray image.



LEGAL STATUS

[Date of request for examination]

03.10.2005

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]